Docket No.: P2001,0126

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : ULRICH BAIER

Filed : CONCURRENTLY HEREWITH

Title : METHOD FOR ETCHING A HARD MASK LAYER AND A METAL

LAYER

## **INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

- U.S. Patent No. 6,159,863 (Chen et al.), dated December 12, 2000;
- U.S. Patent No. 5,468,686 (Kawamoto), dated November 21, 1995;
- U.S. Patent No. 4,915,779 (Srodes et al.), dated April 10, 1990;
- U.S. Patent No. 4,335,506 (Chiu et al.), dated June 22, 1982;
- U.S. Patent No. 6.136,211 (Qian et al.), dated October 24, 2000;
- U.S. Patent No. 5,776,832 (Hsieh et al.), dated July 7, 1998;

PCT WO 96/27899 (Costaganna et al.), dated September 12, 1996;

International Search Report, dated July 25, 2002.

If no translation of pertinent portions of any foreign language patents or publications mentioned above is included with the aforementioned copies of those applications, patents and/or publications, it is because no existing translation is readily available to the applicant.

Respectfully submitted,

For Applicant

Date: August 25, 2003

Lerner and Greenberg, P.A. Post Office Box 2480 Hollywood, FL 33022-2480

Tel: (954) 925-1100 Fax: (954) 925-1101

/nt/kf

LAURENCE A. GREENBERG REG. NO. 29,308

FORM PTO-1449 (SUBSTITUTE)				Attorney Docket No.: P2001,0126 Appl. No.:				
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE								
				Applicant: ULRICH BAIER				
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Applicant. SERICH BAIER				
(37 CFR 1.98(b))				Filing Date: August 25, 2003				
				Group Art Unit:				
EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB	FILI	
MITTALS	Α	6,159,863	12/12/00	Chen et al.	1	92.100		
	В	5,468,686	11/21/95	Kawamoto				
	С	4,915,779	4/10/90	Srodes et al.				
	D	4,335,506	6/22/82	Chiu et al.				
	E	6,136,211	10/24/00	Qian et al.				
	F	5,776,832	7/7/98	Hsieh et al.				
	G							
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FOREIGN PATENT DOCUMENT								
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRA	
	J	96/27899	9/12/96	WIPO				
	K							
	L							
	М							
	N			<u> L</u>	<u> </u>	L		
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)								
EXAMINER				DATE CONSIDERED				

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.